

AOD409/AOI409

60V P-Channel MOSFET

General Description

Trench Power MV MOSFET technology

• Low R_{DS(ON)}

Low Gate Charge

Optimized for fast-switching applications

Product Summary

 $\begin{array}{ll} V_{DS} & -60V \\ I_D \ (at \ V_{GS} \text{=-}10V) & -26A \\ R_{DS(ON)} \ (at \ V_{GS} \text{=-}10V) & <40 \text{m}\Omega \end{array}$

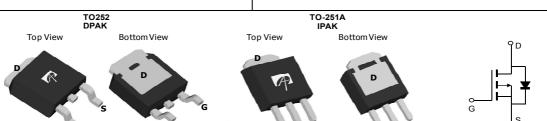
 $R_{DS(ON)}$ (at V_{GS} =-4.5V) < 55m Ω

Applications

Synchronus Rectification in DC/DC and AC/DC Converters

Industrial and Motor Drive applications





Orderable Part Number	Package Type	Form	Minimum Order Quantity		
AOD409	TO-252	Tape & Reel	2500		
AOI409	TO-251A	Tube	4000		

Absolute Maximum Ratings T _A =25°C unless otherwise noted						
Parameter		Symbol	Maximum	Units		
Drain-Source Voltage		V _{DS}	-60	V		
Gate-Source Voltage		V _{GS}	±20	V		
Continuous Drain	T _C =25°C		-26			
Current	T _C =100°C	I _D	-18	A		
Pulsed Drain Current C		I _{DM}	-80			
Avalanche Current ^C		I _{AS}	-26	A		
Avalanche energy	L=0.1mH ^C	E _{AS}	34	mJ		
	T _C =25°C	P _D	60	W		
Power Dissipation ^B	T _C =100°C	F _D	30	VV		
	T _A =25°C	D	2.5	W		
Power Dissipation A	T _A =70°C	P _{DSM}	1.6	VV		
Junction and Storage Temperature Range T		T _J , T _{STG}	-55 to 175	°C		

Thermal Characteristics						
Parameter		Symbol	Тур	Max	Units	
Maximum Junction-to-Ambient A	t ≤ 10s	В	16.7	25	°C/W	
Maximum Junction-to-Ambient AD	Steady-State	$R_{\theta JA}$	40	50	°C/W	
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	1.9	2.5	°C/W	



Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC PARAMETERS							
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =-250μA, VGS=0V		-60			V
I _{DSS} Zero G	Zero Gate Voltage Drain Current	V _{DS} =-48V, V _{GS} =0V				-1	μA
	Zero Gate Voltage Drain Current	T	_J =55°C			-5	μζ
I_{GSS}	Gate-Body leakage current	V_{DS} =0V, V_{GS} =±20V				±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=-250\mu A$		-1.2	-1.9	-2.4	V
$I_{D(ON)}$	On state drain current	V _{GS} =-10V, V _{DS} =-5V		-80			Α
		V _{GS} =-10V, I _D =-20A			32	40	mΩ
$R_{DS(ON)}$	Static Drain-Source On-Resistance		=125°C		53		11152
		V_{GS} =-4.5V, I_{D} =-20A			43	55	mΩ
g _{FS}	Forward Transconductance	V_{DS} =-5V, I_{D} =-20A			32		S
V_{SD}	Diode Forward Voltage	I _S =-1A,V _{GS} =0V			-0.73	-1	V
Is	Maximum Body-Diode Continuous Current					-30	Α
DYNAMIC	PARAMETERS						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =-30V, f=1MHz			2977	3600	pF
Coss	Output Capacitance				241		pF
C _{rss}	Reverse Transfer Capacitance				153		pF
R_g	Gate resistance	f=1MHz			2	2.4	Ω
SWITCHI	NG PARAMETERS						
$Q_g(10V)$	Total Gate Charge				44	54	nC
Q _g (4.5V)	Total Gate Charge	V _{GS} =-10V, V _{DS} =-30V, I _D =-20A			22.2	28	nC
Q_{gs}	Gate Source Charge		20/1		9		nC
Q_{gd}	Gate Drain Charge]			10		nC
$t_{D(on)}$	Turn-On DelayTime				12		ns
t_r	Turn-On Rise Time	V_{GS} =-10V, V_{DS} =-30V, R_L =1.5 Ω , R_{GEN} =3 Ω			14.5		ns
$t_{D(off)}$	Turn-Off DelayTime				38		ns
t _f	Turn-Off Fall Time				15		ns
t _{rr}	Body Diode Reverse Recovery Time	I _F =-20A, dI/dt=100A/μs			40	50	ns
Q_{rr}	Body Diode Reverse Recovery Charge	l _F =-20A, dl/dt=100A/μs			59		nC

A. The value of $R_{\theta,lA}$ is measured with the device mounted on $1in^2$ FR-4 board with 2oz. Copper, in a still air environment with T_A =25° C. The Power dissipation P_{DSM} is based on R $_{\theta,lA}$ \leq 10s and the maximum allowed junction temperature of 150° C. The value in any given application depends on the user's specific board design, and the maximum temperature of 175° C may be used if the PCB allows it.

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B. The power dissipation P_D is based on $T_{J(MAX)}$ =175° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature $T_{J(MAX)}$ =175° C.

D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

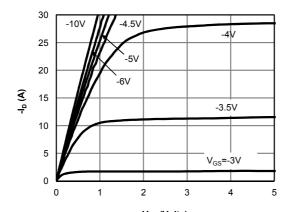
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T_{J(MAX)}=175° C. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

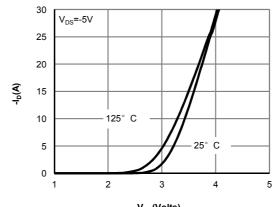
H. These tests are performed with the device mounted on 1 in FR-4 board with 2oz. Copper, in a still air environment with T_A =25° C.



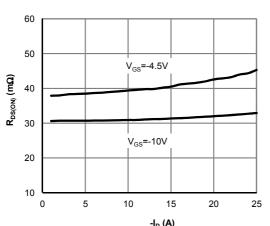
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



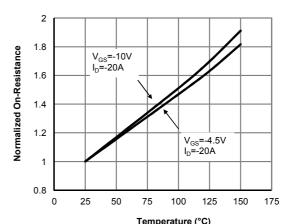
-V_{DS} (Volts) Figure 1: On-Region Characteristics (Note E)



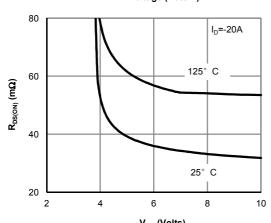
-V_{GS}(Volts)
Figure 2: Transfer Characteristics (Note E)



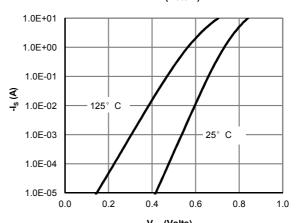
-I_D (A) Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)



Temperature (°C)
Figure 4: On-Resistance vs. Junction Temperature
(Note E)



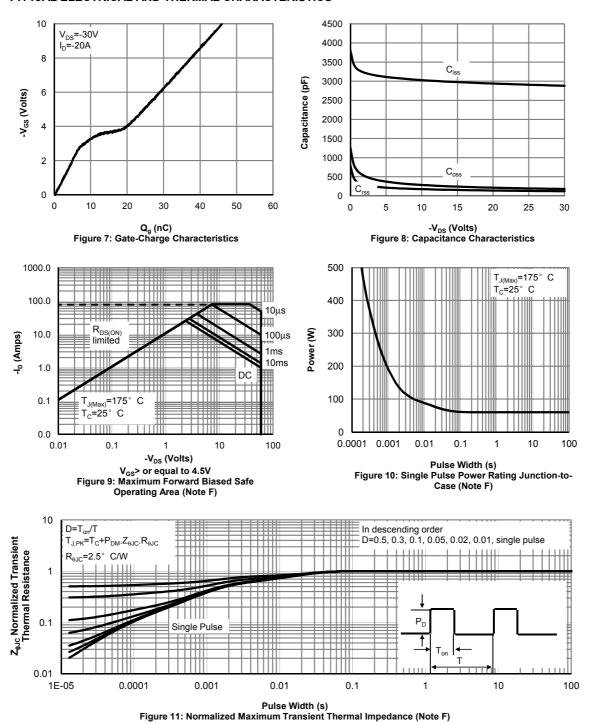
-V_{GS} (Volts)
Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)



-V_{SD} (Volts) Figure 6: Body-Diode Characteristics (Note E)



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



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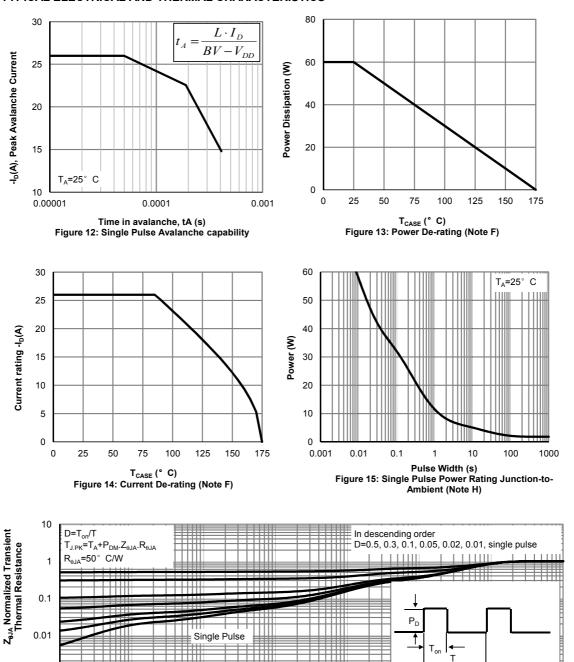
0.001

0.0001

0.001

0.01

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



Pulse Width (s)
Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

10

0.1

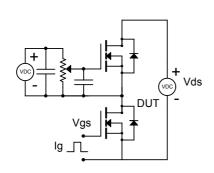
1000

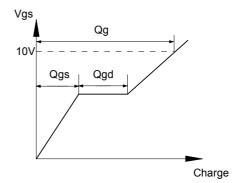
100

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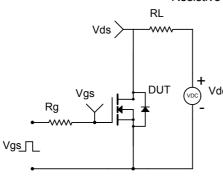


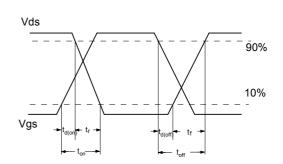
Gate Charge Test Circuit & Waveform



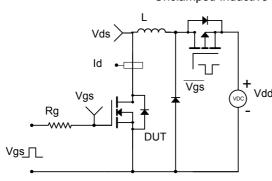


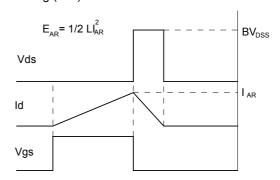
Resistive Switching Test Circuit & Waveforms



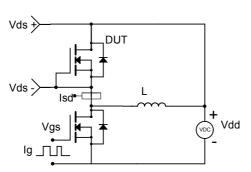


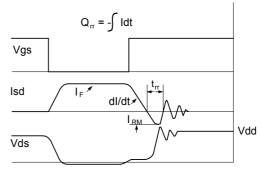
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





Diode Recovery Test Circuit & Waveforms





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